

1W, L/S-BAND
MEDIUM POWER GaAs HJ-FET

NE6510179A

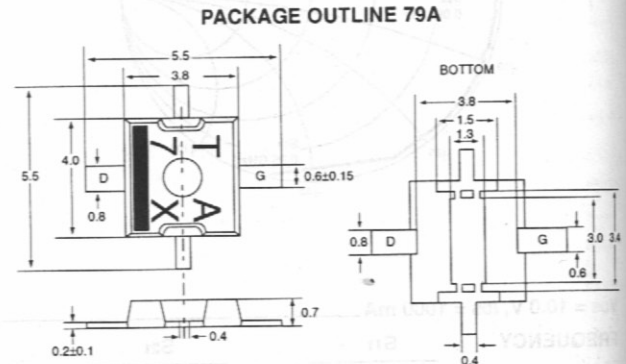
FEATURES

- **LOW COST PLASTIC SURFACE MOUNT PACKAGE**
- **HIGH OUTPUT POWER:** +31.5 dBm TYP @ $V_{DS} = 3.5\text{ V}$, $I_{DSQ} = 150\text{ mA}$, $f = 850\text{ MHz}$, $P_{in} = +20\text{ dBm}$
+32.0 dBm TYP @ $V_{DS} = 3.2\text{ V}$, $I_{DSQ} = 200\text{ mA}$, $f = 1760\text{ MHz}$, $P_{in} = +24\text{ dBm}$
- **HIGH LINEAR GAIN:** 14 dB TYP @ $V_{DS} = 3.5\text{ V}$, $I_{DSQ} = 150\text{ mA}$, $f = 850\text{ MHz}$, $P_{in} = 0\text{ dBm}$
10 dB TYP @ $V_{DS} = 3.2\text{ V}$, $I_{DSQ} = 200\text{ mA}$, $f = 1760\text{ MHz}$, $P_{in} = 0\text{ dBm}$
- **HIGH POWER ADDED EFFICIENCY:** 70% TYP @ $V_{DS} = 3.5\text{ V}$, $I_{DSQ} = 150\text{ mA}$, $f = 850\text{ GHz}$, $P_{in} = +20\text{ dBm}$
60% TYP @ $V_{DS} = 3.2\text{ V}$, $I_{DSQ} = 200\text{ mA}$, $f = 1760\text{ GHz}$, $P_{in} = +24\text{ dBm}$
- **CLASS AB OPERATION**
- **TAPE & REEL PACKAGE OPTION AVAILABLE**

DESCRIPTION

The NE6510179A is a 1 W GaAs HJ-FET designed for medium power transmitter applications for mobile communication systems. It is capable of delivering 1 watt of output power (CW) with high linear gain, high efficiency, and excellent distortion. Reliability and performance uniformity are assured by NEC's stringent quality and control procedures.

OUTLINE DIMENSIONS (Units in mm)



Note: Unless otherwise specified, tolerance is $\pm 0.2\text{ mm}$.

ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$)

PART NUMBER PACKAGE OUTLINE				NE6510179A 79A			TEST CONDITIONS
FUNCTIONAL CHARACTERISTICS	SYMBOLS	CHARACTERISTICS	UNITS	MIN	TYP	MAX	
	Functional Characteristics	P_{OUT}	Output Power	dBm		31.5	
GL		Linear Gain ¹	dB		14		
η_{ADD}		Power Added Efficiency	%		70		
I_D		Drain Current	A		0.53		
Electrical DC Characteristics	I_{DSS}	Saturated Drain Current	A		2.4		$V_{DS} = 2.5\text{ V}$; $V_{GS} = 0\text{ V}$
	V_P	Pinch-Off Voltage	V	-2.0		-0.5	$V_{DS} = 2.5\text{ V}$; $I_D = 14\text{ mA}$
	R_{TH}	Thermal Resistance	$^\circ\text{C/W}$		10		Channel to Case

Notes:

1. $P_{in} = 0\text{ dBm}$
2. DC performance is 100% testing. RF performance is testing several samples per wafer. Wafer rejection criteria for standard devices is 1 reject for several samples.